

Search Notes

Application No.

10/082,745

Examiner

Maikhanh Nguyen

Applicant(s)

POSH ET AL.

Art Unit

2176

SEARCHED

Class	Subclass	Date	Examiner
715	530	1/16/2005	MK
	540	1/25/2005	MK
715	724	1/25/2005	MK
	769	1/25/2005	MK
	770	1/25/2005	MK
Updated	Search	5/4/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
West Search	1/16/2005	MK
West Search	1/25/2005	MK
NPL (IEEE)	1/25/2005	MK
Consulted with Primary Examiner Doug Hutton	2/21/2006	MK
Consulted with Primary Examiner William Bashore	5/3/2006	MK
West Updated Search (USPAT, US- GPUB, EPO, JPO, DERWENT, IBM_TDB)	5/4/2006	MK

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Applicant(s)/Patent under
Reexamination

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SEARCHED

Class	Subclass	Date	Examiner
Updated	Search	7/1/2005	MK
Updated	Search	5/8/2006	MK
715	718	5/8/2006	MK
715	769	5/8/2006	MK

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
QEM	6/30/2005	MK
Consulted with SPE Stephen Hong	6/30/2005	MK
Consulted with Primary Examiner William Bashore	7/1/2005	MK
West Search	6/30/2005	MK
West Search	7/1/2005	MK
Consulted with Primary Examiner Doug Hutton	1/3/2006	MK
Consulted with Primary Examiner William Bashore	5/4/2006	MK
West Updated (USPAT, USPGPUB, EPO, JPO, DERWENT, IBM_TDB)	5/8/2006	MK